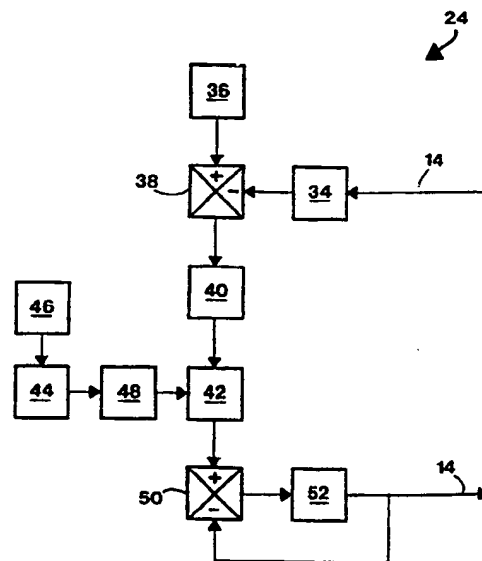




## INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

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<b>(21) International Application Number:</b> PCT/US90/02761 <b>(22) International Filing Date:</b> 21 May 1990 (21.05.90)  <b>(71)(72) Applicant and Inventor:</b> UNDERWOOD, Marcos, A. [US/US]; 21850 Byrne Court, Cupertino, CA 95014 (US).  <b>(74) Agent:</b> HUGHES, Michael, J.; Intellectual Property Law Office of Michael J. Hughes, 2350 Mission College Boulevard, Suite 1150, Santa Clara, CA 95054 (US).  <b>(81) Designated States:</b> AT (European patent), BE (European patent), CA, CH (European patent), DE (European patent)*, DK (European patent), ES (European patent), FR (European patent), GB (European patent), IT (European patent), JP, LU (European patent), NL (European patent), SE (European patent).		<b>Published</b> <i>With international search report.</i>
<b>(54) Title:</b> ADAPTIVE CONTROL METHOD FOR MULTIEXCITER SINE TESTS  <b>(57) Abstract</b>  <p>A multiexciter digitally swept-sinewave vibration test controller employing an adaptive control method which compensates for nonlinear and time variant physical characteristics of a system under test and for instrumentation errors. A system under test (12) is stimulated using an exciter array (26) and response is measured using a sensor array (28). The exciter array (26) is driven by signals produced by a digital vector swept oscillator (18). A control loop (14) is used to modify signals to the exciter array (26) based upon input from the sensor array (28). A digital processing system (24) processes signals in the control loop (14). Within the digital processing system (24), a system impedance matrix (44) containing values representing the inverse of response characteristics of the system under test (12) is updated to approximate an "actual" system impedance matrix. A drive signal matrix (52) is modified to cause the digital vector swept oscillator (18) to produce updated drive signals. An amount by which the updated system impedance matrix (44) is allowed to modify each iteration of the drive signal matrix (52) is controlled by a variable adjustment gain scalar (48). Value of the adjustment gain scalar (48) is determined using values obtained in a preceding iteration of the control cycle.</p>		



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**ADAPTIVE CONTROL METHOD FOR MULTIEXCITER SINE TESTS****TECHNICAL FIELD**

The present invention relates generally to a method for correcting for nonlinearity in system characteristics during a vibration test, and more particularly to a method for accurately controlling stimuli applied by a multiexciter swept-sinewave control system so as to keep a resultant response matrix within acceptable limits. The predominant current usage of the adaptive control method for multiexciter swept sine tests of the present invention is in controlling the forces applied in the process of vibration stress analysis of engineered articles of manufacture.

**BACKGROUND ART**

Numerous factors have combined to create a need for increasingly accurate and repeatable stress and vibration testing of structures and devices. Among these are the trend to build things lighter and stronger, the increasing usage of new and untested materials, and an increasing awareness of the need for predictability and safety in the design and manufacture of products. Therefore, the field of vibration testing is rapidly advancing. Vibration testing is performed on actual items of manufacture where size and economy permit. Where this is not feasible, vibration testing may be performed on scale models or mock ups of items thought to have the same relative resistance to vibration as the actual items of interest.

U.S. Patent Nos. 3,710,082, and 3,848,115, both issued to Sloane et al., are concerned with the process of controlling essentially random signals with the objective of maintaining an overall spectral density of a vibration pattern within acceptable limits. Such an approach recognizes the random nature of many naturally occurring vibration sources. While this conceptual approach is perfectly valid and correct, it has been recognized that a more precisely defined stimulus might lead to a higher degree of repeatability in testing. One approach that has been

1    tried is to use motive stimulus defined by sine waves. Any  
2    complex wave can be synthesized using a combination of sine  
3    waves. Therefore, a multiexciter system with each exciter  
4    being driven by precisely controlled sums of sine waves  
5    could, theoretically, produce any desired complex vibration  
6    pattern in a structure. In a multiexciter system, stimulus,  
7    and response are best described by vectors of dimension  $N$  and  
8    impedance factors are best described by a matrix of  $N$  by  $N$   
9    dimensions, with  $N$  being the number of stimulus/response  
10   points involved.

11        The objective of a multiexciter swept-sinewave test is  
12   to impart a controlled stimulus to a structure at specified  
13   points via a series of actuators. A desired stimulus can be  
14   represented as a complex vector spectrum. A multiexciter  
15   controller, through feedback, continuously excites the  
16   structure, measures the response spectral vector at the  
17   control points, and modifies the drive signal spectral vector  
18   until the response vector agrees with the desired stimulus  
19   vector to within some acceptable error tolerance.

20        In the past, these tests have been performed using  
21   purely analog means. In the analog systems, phase  
22   relationships between response points were controlled by  
23   inducing phase shifts between the drive signal components as  
24   a function of the phase difference between the response  
25   points. However, the analog approach proved to be largely  
26   unsuccessful at frequencies near structural resonance  
27   frequencies, since cross coupling effects between the drive  
28   signal components and the structure's frequency response  
29   characteristics were not accounted for.

30        More recently, digital approaches have been tried with  
31   greater success. The most important reason for the success  
32   of digital control systems in these applications is that  
33   digital systems can employ a feedback control algorithm that  
34   accounts for structural cross coupling effects by using a  
35   structural frequency response matrix measured before the  
36   test. U.S. Patent No. 4,782,324, issued to the present  
37   inventor, teaches a method and apparatus for converting a  
38   digital signal into an analog signal useful for vibration  
39   exciter stimulation.

40   ///

1           However, even the currently available digital control  
2 systems will not provide the desired degree of control when  
3 applied to nonlinear and/or time varying systems because the  
4 frequency response matrix estimate used by the control system  
5 may differ from the actual frequency response matrix existing  
6 during the test. For instance, nonlinear stiffness effects  
7 will generally cause a shift in the resonant frequency that  
8 will cause a large deviation in the phase of the measured  
9 frequency response matrix as compared to the response matrix  
10 which the control system actually encounters as it is  
11 conducting the swept sine test. These potentially large  
12 phase discrepancies can cause control system instabilities.  
13 Further, imperfections in controller drive and response  
14 circuits can lead to undetected inaccuracies in conventional  
15 systems. Clearly, there is a need to be able to dynamically  
16 compensate for nonlinear and time variant deviations in a  
17 structure response matrix during vibration testing, and to  
18 detect and correct for other system inaccuracies.

19           All of the prior art systems for digitally controlling  
20 multiexciter swept-sinewave vibration testing within the  
21 inventor's knowledge have employed a predetermined and set  
22 structural frequency response matrix.

23           No prior art controller to the inventor's knowledge has  
24 successfully compensated for non linear or time variant  
25 factors in a system frequency response matrix. All  
26 multiexciter swept-sinewave vibration test controllers to  
27 date have suffered a high degree of inaccuracy or instability  
28 when encountering such variable factors, especially near  
29 structural resonance frequencies.

30

#### 31                           DISCLOSURE OF INVENTION

32

33           Accordingly, it is an object of the present invention  
34 to provide a controller for multiexciter swept-sinewave  
35 vibration testing which will produce a desired complex  
36 stimulus vector spectrum at a full range of frequencies  
37 including those near structural resonance.

38           It is another object of the present invention to  
39 provide a controller for multiexciter swept-sinewave  
40 vibration testing which will correct for instrumentation

1 errors, such as low matching of phase and amplitude between  
2 driver input channels, low coherence between exciter drive  
3 vector and control point response vector, and low dynamic  
4 range of the input and output channels.

5 It is still another object of the present invention to  
6 provide a means for dynamically adjusting a drive signal  
7 spectral vector in a multiexciter swept-sinewave vibration  
8 test to compensate for non linear and time variant  
9 characteristics of the structure under test.

10 It is yet another object of the present invention to  
11 provide a means to correct for factors in a multiexciter  
12 swept-sinewave test control system which would tend to cause  
13 a drive signal spectral vector to vary from a desired  
14 stimulus spectral vector.

15 Briefly, the preferred embodiment of the present  
16 invention is a digitally controlled multiexciter swept-  
17 sinewave vibration test controller employing the inventive  
18 method to refine an estimate of system impedance values  
19 during the control process for causing a control point  
20 response spectral vector to agree with a desired reference  
21 spectral vector. As with previous swept-sinewave  
22 controllers, the inventive controller functions by employing  
23 a feedback control algorithm that accounts for structural  
24 cross coupling effects in a structure under test by using a  
25 structural frequency response matrix. However, the  
26 controller of the present invention has the capability of  
27 adjusting the structural frequency response matrix during  
28 testing and then modifying drive signals accordingly.

29 System stability is insured by application of an  
30 optimization process to the adaptive control process.

31 An advantage of the present invention is that test  
32 reliability and repeatability are enhanced by improved  
33 control of vibration stimuli.

34 A further advantage of the present invention is that  
35 test integrity is maintained even at structural resonance and  
36 anti-resonance frequencies of a structure under test.

37 Yet another advantage of the present invention is that  
38 unacceptable instability is not introduced into a test by  
39 time variant or nonlinear characteristics of a structure  
40 under test.

1        Still another advantage of the present invention is  
2 that inaccuracies and instability due to instrumentation  
3 errors in a controller feedback system are effectively  
4 reduced.

5        These and other objects and advantages of the present  
6 invention will become clear to those skilled in the art in  
7 view of the description of the best presently known modes of  
8 carrying out the invention and the industrial applicability  
9 of the preferred embodiments as described herein and as  
10 illustrated in the several figures of the drawing.

11

12

#### BRIEF DESCRIPTION OF THE DRAWING

13

14        FIG. 1 is a block diagram of a swept-sinewave  
15 controller employing the inventive method; and

16

17        FIG. 2 is a flow diagram showing digital signal  
18 processing steps to implement the inventive method within a  
19 digital signal processing system.

19

20

#### BEST MODE FOR CARRYING OUT INVENTION

21

22        The best presently known mode for carrying out the  
23 invention is a multiexciter swept-sinewave vibration  
24 controller suitable for implementing the inventive adaptive  
25 control method. The predominant expected usage of the  
26 inventive adaptive control method is in the design  
27 experimentation and quality control phases of the production  
28 of structural items and components of items which are  
29 intended to withstand vibration forces. The inventive method  
30 is particularly useful in the testing of relatively large or  
31 complex structures which are capable of complex resonance or  
32 of physical characteristics that vary with time, with  
33 frequency, or with other test parameters.

34        The controller of the presently preferred embodiment of  
35 the present invention is illustrated by means of a block  
36 diagram in FIG. 1 and is designated therein by the general  
37 reference character 10. Also shown in FIG. 1 is a system  
38 under test 12 which, along with the controller 10 form  
39 portions of a closed control loop 14. In many of its  
40 substantial components and processes, the controller 10 does

1 not differ significantly from conventional multiexciter  
2 swept-sinewave controllers. The physical structure is  
3 similar to that of prior art controllers.

4 The conventional elements of the controller 10 include  
5 a digital sweep oscillator 16, a digital vector swept  
6 oscillator 18, a D/A subsystem 20, an A/D subsystem 22 and a  
7 digital processing subsystem 24. Completing the closed  
8 control loop 14 are an exciter array 26 and a sensor array  
9 28. The exciter array 26 is made up of a quantity of  
10 exciters 30 chosen by a user of the controller 10 to be the  
11 most desirable for the system under test 12. The locations  
12 of the exciters 30 on the system under test 12 are also  
13 chosen by the user according to established principles which  
14 form no part of the present invention. For illustrative  
15 purposes, the control loop 14 is shown in FIG. 1 to include  
16 three exciters 30. In this example of a configuration for  
17 usage of the best presently known embodiment 10 of the  
18 inventive controller, the sensor array 28 contains a quantity  
19 of sensors 32 equal to the quantity of exciters 30, being  
20 three in the present example. However, as will be discussed  
21 hereinafter, the present invention may also be used with  
22 "non-square" systems in which the quantities of exciters 30  
23 and sensors 32 are not identical. The sensors 32 are placed  
24 as close as possible to the exciters 30 so as to avoid, as  
25 much as possible, error in the feedback loop 14 resulting  
26 from dissimilarity between motion actually present at the  
27 exciters 30 and that sensed at the sensors 32.

28 During testing, the digital vector swept oscillator 18  
29 modifies a digital equivalent of a sine wave signal created  
30 in the digital sweep oscillator 16 according to input derived  
31 from the digital processing system 24. The D/A subsystem  
32 converts the modified digital equivalent signal into an  
33 analog signal suitable for driving the exciters 30. The  
34 exciters 30 may be any of the commonly available linear or  
35 rotary types of electromechanical exciter devices. The  
36 present inventor's Patent No. 4,782,324 teaches a method and  
37 apparatus for converting a digital signal into a band limited  
38 analog signal which is used in the inventive controller 10.  
39 When the exciters 30 have stimulated the system under test  
40 12, the sensors 32 measure the resultant response. If there



1 were but one exciter 30 and one sensor 32, a response  
2 measured at that one sensor 32 could rightly be considered to  
3 be the effect of the stimulus imparted by the one exciter 30.  
4 However, since in the present example three exciters 30 and  
5 three sensors 30 are used, responses measured at the sensors  
6 32 must be considered to be an N dimensional vector, with N  
7 being the total number of exciter 30 and sensor 32 pairs.  
8 Analog response signals created by the sensors 32 are  
9 converted to digital equivalents by the A/D subsystem 22,  
10 which digital input is provided to the digital processing  
11 system 24.

12 Referring now to FIG. 2, wherein is shown a block flow  
13 diagram of the digital signal processing flow which occurs  
14 within the digital processing system 24, it can be seen that  
15 the outputs of the A/D subsystem 22 are provided to the  
16 digital processing system via the feed-back loop 14 and are  
17 resolved into a control response vector 34. It should here  
18 be noted that the enumerated features of FIG. 2 represent  
19 analog equivalents of the digital manipulation that actually  
20 occurs within the digital processing system 24. The notation  
21 is customary for depicting analog equivalents of digital  
22 signal processing steps. As one familiar with the art of  
23 digital signal processing would appreciate, actual  
24 mathematical functions may be performed in an order not  
25 directly correlative to the analog equivalents depicted.  
26 Transformation of the analog equivalent shown into the  
27 digital signal processing actually performed is according to  
28 well known practices and is not unique to the present  
29 invention. The control response vector 34 is compared to a  
30 reference spectrum vector 36 at a first comparator 38. A  
31 control error vector 40 results from the first comparator 38.  
32 Individual values of the control error vector 40 will be  
33 positive where corresponding reference spectrum vector 36  
34 values are higher than control response vector 34 values, and  
35 negative where reference spectrum vector 36 values are lower  
36 than control response vector 34 values. A compensated error  
37 matrix 42 is produced by adjusting the control error vector  
38 40 according to a system impedance matrix 44. The system  
39 impedance matrix 44 is the set of inverse values of values  
40 contained in a system response matrix 46. Initial values for

1 the system response matrix 46 are determined prior to  
2 beginning a test by stimulating the system under test 12  
3 sequentially with individual exciters 30 and measuring the  
4 response of the system 12 at each sensor 32. An adjustment  
5 gain scalar 48 is the factor by which the control error  
6 vector 40 is adjusted by the system impedance matrix 44.  
7 Means for adjusting the control error vector 40 by the system  
8 impedance matrix 44 are well known and practiced in the art,  
9 and are not unique to the present invention.

10 The compensated error matrix 42 is provided to a second  
11 comparator 50. The second comparator 50 produces an updated  
12 drive signal 52 which is provided as an output to the feed-  
13 back loop 14. It is important to note that the operation  
14 described above is both cyclical and continuous in nature,  
15 and that the updated drive signal vector 52 being  
16 instantaneously provided to the feedback loop 14 is also  
17 provided as an input to the second comparator 50 such that  
18 each succeeding cycle has as one component of the updated  
19 drive signal vector 52 the updated drive signal vector 52 of  
20 the previous cycle.

21 In mathematical terms the above described functioning  
22 of the digital processing system 24 can be described as  
23 follows:

24

25 
$$\{D_{n+1}(f)\} = \{D_n(f)\} + g[Z_m(f)]\{R(f)\} - \{C_n(f)\}$$

26 where;

27  $D_n(f)$  = current values of the updated drive signal 52;

28  $D_{n+1}(f)$  = next subsequent values of the updated drive  
29 signal 52;

30  $g$  = value of the adjustment gain scalar 48;

31  $Z_m(f)$  = values of the system impedance matrix estimate  
32 44;

33  $R(f)$  = values of the reference spectrum vector 36;

34  $C_n(f)$  = values of the control response vector 34; and

35 where the subscript "n" represents the number of the  
36 current repetition and the subscript "m" represents the  
37 fact that the associated quantities are measured and  
38 determined prior to beginning the first test cycle.

39 ////

40 ////

1           It has been the practice in the industry to determine  
2 the value of the adjustment gain scalar 48 at the outset of  
3 the test to be a value "g" which is sufficiently large to  
4 result in a reasonably quick system convergence, while  
5 remaining small enough to reduce potential instability  
6 problems caused by repeated excessive over correction of the  
7 compensated error matrix 42 and, thus, of the updated drive  
8 signal vector 52. Note that negative values of "g" have to  
9 be used when phase errors greater than 90° are present in  
10 measured values of the system response matrix 46. Further,  
11 the values of the system response matrix 46 have also  
12 heretofore been fixed during the test at values set prior to  
13 the beginning of the test, as explained previously herein.

14           However, as is also explained previously herein, while  
15 the digital processing system 24, as defined thus far, will  
16 attempt to cause the control response vector 34 to converge  
17 on the reference vector 36 values, it implicitly uses  
18 assumptions that the system impedance matrix 44 is an  
19 accurate measure of actual system characteristics under  
20 dynamic test conditions. As discussed previously, this may  
21 not be a good assumption, particularly over time as overall  
22 system conditions, such as frequency and magnitude of input  
23 stimuli, vary.

24           Therefore, in accordance with the method of the present  
25 invention, a series of system response matrices 46 is  
26 produced which converge to the inverse of an "actual" system  
27 frequency response matrix "H(f)" (not shown). As will be  
28 discussed hereinafter, an "actual" system response matrix,  
29 because it may continually vary and because it is not  
30 amenable to precise measurement, cannot be precisely defined,  
31 and trying to define it is best viewed as a goal that can  
32 never quite be achieved. Further, the presently preferred  
33 embodiment of the present invention employs a variable  
34 complex value for the adjustment gain scalar 48 which can  
35 compensate for phase errors that can exist in updated system  
36 response matrices 46 during early stages of the update  
37 process, instead of the fixed value "g". The difficulty in  
38 the process arises from the fact that any obvious approaches  
39 to this require that the indefinable "actual" system response  
40 matrix be known. The inventor has applied aspects of

1 optimization theory with aspects of control problem theory  
 2 and an application of an algorithm that attempts to minimize  
 3 an objective function to derive the unique process described  
 4 herein which provides a means for accomplishing this  
 5 seemingly impossible control dilemma.

6 According to the method of the present invention, the  
 7 system impedance matrix 44 is updated according to the  
 8 formula:

$$[Z_{n+1}(f)] = ([I_N] + \frac{([S_n(f)] - [Z_n(f)]([C_{n+1}(f)] - \{C_n(f)\}))([S_n(f)]^*)}{\langle [Z_n(f)]([C_{n+1}(f)] - \{C_n(f)\}), [S_n(f)] \rangle}) [Z_n(f)]$$

14 where:

15  $S_n(f)$  = values of the compensated error vector 40;

16  $Z_n(f)$  = values of the system impedance matrix 44;

17  $C_{n+1}(f)$  = next subsequent values of the control response  
 18 vector 34;

19  $C_n(f)$  = present values of the control response vector 34;

20  $Z_n(f)$  = present values of the system impedance matrix 44;

21  $Z_{n+1}(f)$  = next subsequent values of the system impedance  
 22 matrix 44;

23  $I_N$  = the N dimensional identity matrix with N being the  
 24 number of exciters 30 and sensors 32 in use.

25  
 26  
 27 It should be noted that, in accordance with the usage  
 28 of the present invention, values of the compensated error  
 29 vector 40 may properly also alternately be referred to as a  
 30 vector "step" magnitude and direction because:

$$[S_n(f)] = a_n[Z_n(f)]([R(f)] - \{C_n(f)\}) = [D_{n+1}(f)] - [D_n(f)]$$

31 where;

32  $a_n$  = present value of the adjustment gain scalar 48.

33  
 34  
 35 In other words, the compensated error vector 40 is the  
 36 amount by which values of the drive signal vector 52 are  
 37 "stepped" between each cycle.

38 Values of the (variable) adjustment gain scalar 48 are  
 39 determined by using a variation of a classic steepest decent  
 40

1 approach according to a formula and method described  
2 hereinafter. The resulting value  $a_n$  is a steepest decent  
3 complex gain value for the adjustment gain scalar 48.  
4 Application of this method results in a change in control  
5 error matrix 42 values between two successive control loop  
6 iterations which are strictly non-negative. This means that  
7 control error matrix 42 values will decrease even for  
8 arbitrary invertible values of the system impedance matrix  
9 44. This helps to assure that the controller 10 will be  
10 stable. The use of a complex number for  $a_n$  is a refinement of  
11 the previously mentioned technique of using negative values  
12 of gain where phase deviation between values of the system  
13 response matrix 46 exceeds  $90^\circ$ .

14 Furthermore, the vectors  $\{S_n(f)\} = a_n[Z_n(f)]\{R(f) -$   
15  $\{C_n(f)\}\}$  can be shown to be conjugate, since they are the  
16 outcome of a steepest descent approximate Hessian algorithm.  
17 Also, the impedance update,  $[Z_{n+1}(f)]$  satisfies the secant  
18 equation:

19

$$20 \quad [Z_{n+1}(f)]\{C_{n+1}(f) - \{C_n(f)\}\} = \{S_n(f)\}$$

21

22 These two conditions guarantee (hypothetically) that  
23 the system impedance matrix 44 will converge to the "actual"  
24 impedance matrix within N steps, where N is the number of  
25 independent exciters 30 that are being used to conduct the  
26 test, if the underlying system being controlled is both  
27 linear and time invariant.

28 The above described steps result in a method for  
29 estimating the impedance of the system 12 during the control  
30 process. The process is essentially stable and, converges in  
31 at most N iterations for linear and time invariant systems  
32 12. In the event the system under test 12 is nonlinear or  
33 time variant, the method will track the impedance of the  
34 system 12 as it varies with drive and control response  
35 amplitudes and frequencies. Obviously, the controller 10  
36 will not converge exactly in a finite number of steps.

37 The one remaining unresolved problem in the basic  
38 scheme is that values of the complex quantity  $a_n$  depend upon  
39 an unknown which is, generally, just as unknown as the  
40 "actual" system response matrix  $[H(f)]$ . To solve this

dilemma, the inventor has employed a "two step control loop" wherein a "learning" loop is used to determine a value which is then used to calculate  $a_n$ , which is then used in a "control" loop. The "control" loop uses  $a_n$  to correct as much of any remaining error as is possible. The result of the "control" loop is then used to update impedance estimates followed by yet another "learning" loop. The cycle is repeated until the system 12 is brought under control.

To accomplish the "two step control loop" process, a variation of the classical multiexciter control update discussed previously is used:

12

13

$$\{D_n(f)\} = \{D_n(f)\} + c_n[Z_n(f)](\{R(f)\} - \{C_n(f)\})$$

15 where;

16

$\{D_n(f)\}$  = values of the drive signal vector 52 for the "learning" loop; and

$c_n$  = value of the adjustment gain scalar 48 for the "learning" loop.

21

In the presently preferred embodiment of the invention, an initial value of approximately .1 is chosen for  $c_n$  in order to minimize control errors associated with using a possibly erroneous impedance estimate in the system impedance matrix 44. Values of  $c_n$  are allowed to increase as confidence in the accuracy of values within the system impedance matrix 44 is increased. Following the "learning" loop, the system under test 12 will respond with a "feedback" loop response value of the control response vector 34:

31

$$\{C_n(f)\}$$

From this, a value for the variable adjustment gain scalar 48 can be calculated as follows:

35

36

37

38

39

40

$$a_n = \frac{c_n \langle (\{R(f)\} - \{C_n(f)\}), (\{C_n(f)\} - \{C_n(f)\}) \rangle}{||\{C_n(f)\} - \{C_n(f)\}||^2}$$

1       As confidence in the values of the variable system  
2 impedance matrix 44 increases, as measured by the value of  
3  $a_n$ , the value of  $c_n$  is allowed to approach 1.0. It should be  
4 noted that an additional benefit can be derived from  
5 monitoring the value of  $a_n$ . Since, as previously discussed,  
6 values of the "actual" system response  $[H(f)]$  cannot be known  
7 exactly, it is useful to note that the value of  $a_n$  is the  
8 best indicator of the instant reliability of the current  
9 working values of the system response matrix  $[Z_n(f)]$  46.

10       The results described herein are relatively independent  
11 of the initial value chosen for  $c_n$  and the rate at which it  
12 is allowed to approach 1.0. However, obviously too small a  
13 value for  $c_n$  will cause ill-conditioning of the  $a_n$   
14 calculation, and too large a  $c_n$  makes the controller 10 too  
15 sensitive to system nonlinearities. Therefore, care in  
16 choosing these values must still be exercised, and only some  
17 minor experimentation with each different system will suffice  
18 to try to optimize these values.

19       As described herein, a process for obtaining and using  
20 all necessary values to achieve the described objectives can  
21 be achieved by the interdependent steps of the inventive  
22 process. All of the quantities required are available during  
23 either the "learning" loop or the "control" loop. Use of the  
24 inventive method does potentially increase control error  
25 during initial iterations due to potential errors in initial  
26 values assigned to the system response matrix 44. Careful  
27 selection of values for  $c_n$  minimizes this problem.

28       Remaining problems to be addressed concerning the  
29 present invention relate to sources of inaccuracy that are  
30 inherent in any similar multiexciter sine wave type system.  
31 Following is a discussion of how these problems are dealt  
32 with in accordance with the best presently known embodiment  
33 of the present invention.

34       The first such problem is low coherence between the  
35 drive vector matrix 50 and the control point response vector  
36 34. This low coherence results from noise in the measurement  
37 of the control response vector 34 which is independent of  
38 signals resulting from the drive vector 52. This sort of  
39 error is corrected in the best presently known embodiment of  
40 the present invention by employing a a numeric algorithm to

1 synthesize a tracking filter in the digital domain in order  
2 to measure the response at the fundamental frequency of the  
3 drive signal. Algorithms for synthesizing analog filter  
4 equivalents are well known and widely practiced in the  
5 industry. This limits the effects of the contaminating  
6 noise by reducing the bandwidth of the noise to match the  
7 bandwidth of the tracking filter. Results of multiple  
8 complex amplitude measurements are also averaged over several  
9 repetitions to reduce the effects even further. However,  
10 remaining noise still has an effect, and the greatest effect  
11 will result near convergence of the system impedance matrix  
12 44 to the "actual" system impedance.

13 A second such problem to be addressed is the effect of  
14 poor matching between the several electrical channels leading  
15 from the sensors 32. The mismatch is a result mainly of  
16 differences between characteristics of low-pass filters that  
17 are used ahead of the A/D converter channels in the A/D  
18 subsystem 22 to prevent aliasing errors. The inventor has  
19 found that this problem can be corrected by the same means  
20 used with more conventional means of measuring frequency  
21 response matrices. One solution is to use very high quality  
22 components so as to match characteristics of all channels to  
23 some acceptable level, such as  $\pm .1$  dB in amplitude and  $\pm 1.0$   
24 degree in phase. Another workable solution is to use a  
25 software based calibration procedure, such as measuring the  
26 frequency characteristics of the input subsystem and  
27 correcting the input signal estimates thereby. Both methods  
28 have been successfully employed with the present invention.  
29 The best presently preferred embodiment uses the method of  
30 employing high quality components. While this method is the  
31 more costly, it has proven to be preferable.

32 A third such universal problem is that of low input and  
33 output dynamic range. This causes noise to appear on both  
34 the input vector 34 and on signals resulting from the output  
35 vector 52. These problems are caused by finite resolutions  
36 of the A/D subsystem 22 and D/A subsystem 20, or by low  
37 efficiency transducers being used as exciters 30 or sensors  
38 32. The problem is aggravated by the fact that significant  
39 levels of signal component are produced at frequencies other  
40 than the excitation frequency. Presence of these additional



1 signal components results in fundamental frequency response  
2 being described by a small digital value in the A/D subsystem  
3 20. The result is a larger percentage error in the control  
4 response vector 34. The best solution to minimize this  
5 problem has been found to be the use of high-resolution  
6 components such as 16 bit converters in the A/D subsystem 22  
7 and the D/A subsystem 20, and the use of full scale  
8 excursions of high quality transducers consistent with analog  
9 test levels.

10 By employing these several techniques in conjunction  
11 with the inventive method for updating the system impedance  
12 matrix 44 and for selecting appropriate variable values for  
13 the adjustment gain scalar 44 during the test, the inventor  
14 has found that the resulting controller 10 provides a  
15 significant improvement over prior art vibration control  
16 systems.

17 As discussed herein, the controller 10, according to  
18 the present invention, effectively solves the problem of  
19 inaccurate system impedance estimates caused by time variant  
20 or non-linear system characteristics. It should be further  
21 noted that the present invention provides an additional  
22 benefit in that any synergistic effects caused by operating  
23 multiple exciters 30 simultaneously, which could not be  
24 accounted for using prior art technology, are not missed  
25 using the inventive controller 10, since all measurements are  
26 taken under actual operating conditions with all exciters 30  
27 in operation. This last could prove to be one of the more  
28 important advances in the field made by the present  
29 invention.

30 As is shown above, in great part, the controllers 10  
31 according to the present invention closely resemble prior art  
32 conventional multiexciter swept-sinewave controllers in many  
33 respects. The substantial difference exists in the inclusion  
34 of means for updating impedance values and the use of a  
35 complex variable gain factor for buffering modifications to  
36 updated drive signals instead of a constant simple scalar  
37 value. No significant changes of materials are envisioned  
38 nor are any special constructions required.

39 Various modifications may be made to the invention  
40 without altering its value or scope. For example, various

1 initial values of  $c_n$  can be tried to optimize the magnitude  
2 of correction made on each repetitive step. Similarly, use  
3 of lower or higher quality components or lower or higher  
4 resolution digital components than are used in the best  
5 presently known embodiment of the invention, as described  
6 herein, would not change the basic character of the  
7 invention.

8 Of course, the uniqueness of the invention, as  
9 described herein, is not dependent upon use of any particular  
10 quantity, type, or configuration of component parts.

11 Another conceivable change would be to vary the  
12 sequence or nomenclature of quantities described by  
13 mathematical formula herein, without essentially changing the  
14 essence of the described invention.

15 As mentioned previously, while the best presently know  
16 embodiment 10 of the invention has been described herein by  
17 means of an example of use wherein an equal number of  
18 exciters 30 and sensors 32 are employed, the invention  
19 applies equally to "non-square" systems wherein the  
20 quantities of exciters 30 differs from the quantity of  
21 sensors 32 employed. Such a variation would require  
22 considering an impedance matrix to be a N by M dimensional  
23 matrix wherein N represents the quantity of exciters 30 and M  
24 represents the quantity of sensors 32, and making  
25 corresponding changes within the formulas given herein.

26 All of the above are only some of the examples of  
27 available embodiments of the present invention. Those  
28 skilled in the art will readily observe that numerous other  
29 modifications and alterations may be made without departing  
30 from the spirit and scope of the invention. Accordingly, the  
31 above disclosure is not intended as limiting and the appended  
32 claims are to be interpreted as encompassing the entire scope  
33 of the invention.

34

35

#### INDUSTRIAL APPLICABILITY

36

37 The multiexciter swept-sinewave vibration test  
38 controllers according to the present invention are  
39 particularly adapted for controlling the vibrations applied  
40 during vibration testing to structures having less than

1 perfectly stable structural impedance characteristics. The  
2 predominant current usages are for testing the structural  
3 integrity and resistance to vibration of structures  
4 sufficiently large to be subject to significant complex  
5 vibration patterns at or near an expected frequency of  
6 induced vibration.

7 The multiexciter swept-sinewave vibration test  
8 controllers of the present invention may be utilized in any  
9 application wherein conventional multiexciter sine wave  
10 controllers are used. The main area of improvement is in the  
11 ability of the inventive controller to account for nonlinear  
12 and time variant characteristics of the structure under test  
13 such that instability and unreliable test results resulting  
14 from such nonlinear and time variant characteristics are  
15 avoided.

16 The control system 10 of the present invention affords  
17 the additional advantage that it keeps a test structure's  
18 response, at the fundamental frequency, relatively constant,  
19 and thus minimizes both the effects of externally added noise  
20 as well as the contribution of the finite resolution effects  
21 of the A/D subsystem 22 and instrumentation effects.

22 Since the multiexciter digitally sept sine wave  
23 vibration test controllers of the present invention may be  
24 readily constructed and are physically significantly similar  
25 to prior art conventional swept-sinewave controllers, it is  
26 expected that they will be acceptable in the industry as  
27 substitutes for the conventional controllers. Further, since  
28 the controller of the present invention differs substantially  
29 from many existing controllers primarily only in that minor  
30 modifications cause the inventive controller to function  
31 according to the inventive method, it is expected that many  
32 existing controllers may be modified to function in  
33 accordance with the present inventive method. For these and  
34 other reasons, it is expected that the utility and industrial  
35 applicability of the invention will be both significant in  
36 scope and long-lasting in duration.

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In The Claims

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3 1. A method for controlling a plurality of analog sinewave  
4 drive signals in a multiexciter vibration test, comprising  
5 the steps of:

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a. stimulating a system under test with a  
plurality of exciters, each of said exciters being a  
transducer physically attached to an system under test,  
for converting said analog sinewave drive signals into  
mechanical motion;

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b. monitoring a response from said system under  
test using a plurality of sensors, each of said sensors  
being a transducer physically attached to said system  
under test, for converting said response into an analog  
response signal;

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17

c. converting said analog response signal into a  
first digital signal;

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d. modifying said first digital signal as a  
function of a reference spectrum vector and a measured  
system response matrix, said reference spectrum vector  
being a digital equivalent of a desired system motion,  
said measured system response matrix being a digital  
equivalent of a previously calculated system response,  
such that an updated digital signal is produced which is  
a digital equivalent of the analog sinewave drive  
signals required to cause said first digital signal to  
approach agreement with the reference spectrum vector;

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e. converting said updated digital signal into a  
yet another plurality of analog sinewave drive signals  
for again driving said exciters; and

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f. continuously repeating steps a. through e.  
while updating values of said measured system response  
matrix as a function of values obtained during previous  
repetitions, such that a series of said measured system  
response matrices is produced which are used in the  
calculation of a series of said updated digital signals  
for producing a series of said pluralities of said  
analog sinewave drive signals, such that values for use  
in calculating a next subsequent of said updated digital  
signals are being obtained while each of said analog

- 1       sinewave drive signals is being used to excite the  
2       system under test.  
3
- 4   2.    The method of Claim 1, wherein:  
5        steps a. through e. are all accomplished in a less  
6        time than a period of said analog sinewave drive  
7        signals, such that each succeeding of said analog  
8        sinewave drive signals is updated according to its  
9        predecessor.  
10
- 11   3.    The method of Claim 1, and further including:  
12        buffering effects of the measured system response  
13        matrix according to a complex number gain value such  
14        that, when said first digital signal is modified as a  
15        function of the measured system response matrix, values  
16        of said first digital signal are allowed to approach  
17        values of the reference spectrum vector at a rate  
18        determined as a function of a confidence value, said  
19        confidence value being a function of a difference  
20        between an instant set of values of said first digital  
21        signal and a previous set of values of said first  
22        digital signal.  
23
- 24   4.    The method of Claim 3, wherein:  
25        said complex number gain value is determined as a  
26        function of a trial gain value, the reference spectrum  
27        vector, instant values of said first digital signal, and  
28        previous values of said first digital signal.  
29
- 30   5.    The method of Claim 4, wherein:  
31        said trial gain value is, itself, a function of  
32        the instant values of said first digital signal and the  
33        previous values of said first digital signal.  
34
- 35   6.    The method of Claim 1, wherein:  
36        odd numbered repetitions of the method employ a  
37        trial gain value for controlling an amount by which said  
38        first digital signal is modified to produce said updated  
39        drive signal, during which odd numbered repetitions of  
40        the method updated values for said first digital signal

1 are obtained by digitizing the resultant analog response  
2 signal, and also during which odd numbered repetitions  
3 of the method the updated values for said first digital  
4 signal are compared to previous values of said first  
5 digital signal for determining an updated complex number  
6 adjustment scale vector; and

7 even numbered repetitions of the method employ the  
8 just determined updated complex number adjustment scale  
9 vector for controlling an amount by which a previous  
10 updated digital signal is modified by said first digital  
11 signal and the measured system response matrix to  
12 produce an instant updated digital signal, during which  
13 even numbered repetitions of the method the trial gain  
14 value is updated to reflect a confidence factor, said  
15 confidence factor being a function of the amount by  
16 which preceding iterations of said first digital signal  
17 have varied.

18  
19 7. In a method for controlling a cyclical sequence for  
20 producing sets of sinewave drive signal digital equivalents  
21 in a multiexciter sinewave vibration test controller, said  
22 method including the steps of initially establishing a system  
23 impedance matrix estimate and an adjustment gain scalar value  
24 and further including the process of employing a feedback  
25 control algorithm to account for a plurality of structural  
26 cross coupling effects in a system under test by modifying a  
27 control error vector according to said system impedance  
28 matrix estimate, said control error vector being a difference  
29 function between an input response vector and a desired  
30 response vector and said system impedance matrix estimate  
31 being a matrix of values representing said cross coupling  
32 effects, an improvement for compensating for nonlinear and  
33 time variant characteristics of the system under test  
34 including the steps of:

35 a. stimulating the system under test using a  
36 first set of the sinewave drive signals and measuring a  
37 resultant physical response vector, the values of said  
38 first set of sinewave drive signals having been  
39 determined by modifying said control error vector  
40 according to a first proportionate part of said system

1 impedance matrix estimate, said first proportionate part  
2 being the product of said system impedance matrix  
3 estimate multiplied by said adjustment gain scalar  
4 value;

5 b. using the resultant input response vector to  
6 calculate an appropriate value for a variable adjustment  
7 gain complex number value and then stimulating the  
8 system under test using a second set of sinewave drive  
9 signals, said second set of sinewave drive signals  
10 having been determined by modifying said control error  
11 vector according to a second proportionate part of said  
12 system impedance matrix estimate, said second  
13 proportionate part being the product of said system  
14 impedance matrix estimate multiplied by said variable  
15 adjustment gain complex number value; and

16 c. repeating steps a. and b. such that during  
17 each of alternate cycles of the method a new value for  
18 said variable adjustment gain complex number is  
19 obtained, and during each of those cycles during which  
20 said variable adjustment gain complex number is not  
21 being obtained, said variable adjustment gain complex  
22 number is being used to determine said second  
23 proportionate part of said system impedance matrix  
24 estimate.

25

26 8. The improved method of Claim 7, wherein:

27 during alternate cycles of the method, the system  
28 impedance matrix estimate is updated as a function of  
29 the new value of said variable adjustment gain complex  
30 number.

31

32 9. The improved method of Claim 7, wherein:

33 during alternate cycles of the method, the  
34 adjustment gain scalar value is adjusted as a function  
35 of a difference between prior values of said control  
36 error vector.

37

38 10. The improved method of Claim 7, wherein:

39 a drive matrix, values of said drive matrix being  
40 the sets of sinewave drive signal digital equivalents,

- 1 is updated during each cycle of the method by an amount  
2 determined by a step value, said step value being the  
3 control error vector modified by the system impedance  
4 matrix estimate and the adjustment gain scalar value;  
5 said step value is algebraically summed to a  
6 present set of values of said drive matrix to determine  
7 a next subsequent set of values of said drive matrix;  
8 and  
9 said system impedance matrix estimate is updated  
10 on at least alternate cycles of said method according to  
11 measured values of said control error vector.  
12
- 13 11. The improved method of Claim 10, wherein:  
14 the adjustment gain vector value is updated during  
15 each cycle of the method as a function of a difference  
16 between two prior values of the control error vector.  
17
- 18 12. The improved method of Claim 7, wherein:  
19 said system impedance matrix estimate is the set  
20 of inverse values of digitized equivalents of the system  
21 response matrix estimate, said system response matrix  
22 estimate being calculated using data obtained during a  
23 previous cycle of the method.  
24
- 25 13. The improved method of Claim 7, wherein:  
26 said adjustment gain scalar value is a complex  
27 number, such that each value within the system impedance  
28 matrix estimate will approach a corresponding value of  
29 an actual system impedance matrix during each update of  
30 the system impedance matrix estimate, said actual system  
31 impedance matrix being an ideal matrix representing  
32 instantaneous response characteristics of the system  
33 under test.  
34
- 35 14. The improved method of Claim 12, wherein:  
36 values of the adjustment gain scalar are monitored  
37 as an indicator of instant reliability of the system  
38 impedance matrix estimate.  
39
- 40 15. In a system for inducing controlled vibration patterns



1 in an article under test, said system including a plurality  
2 of exciters physically attached to the article under test for  
3 producing a physical motion in the article under test, a  
4 plurality of sensors physically attached to the article under  
5 test for sensing a resultant motion, an A/D subsystem for  
6 converting analog sensor output into a digital output  
7 equivalent of sensor output, a digital controller for  
8 monitoring digital output from the A/D subsystem and for  
9 producing a digital equivalent of a drive signal, and a D/A  
10 subsystem for converting said digital equivalent of a drive  
11 signal into an analog drive signal for powering the exciters,  
12 said drive signal being a plurality of sinewaves with each of  
13 said sinewaves being modified in phase and amplitude by the  
14 digital controller such that said resultant motion tends to  
15 conform to a predetermined desired motion, an improvement  
16 comprising:

17 a first comparator means, logically situated first  
18 within said digital controller such that said first  
19 comparator means has as one of its inputs the digital  
20 output from the A/D subsystem, for comparing a control  
21 response vector to a reference spectrum vector and for  
22 producing a control error vector as an output, said  
23 control error vector representing the difference between  
24 said control response vector and said reference spectrum  
25 vector, said control response vector being a digital  
26 equivalent of said resultant motion and said reference  
27 spectrum vector being a digital equivalent of said  
28 predetermined desired motion;

29 a buffering means, logically situated within said  
30 digital controller after said first comparator means,  
31 for modifying a system impedance matrix according to an  
32 adjustment gain value and said control error vector and  
33 for producing a compensated error matrix as an output,  
34 said system impedance matrix containing inverse values  
35 of a temporal system response matrix estimate, said  
36 adjustment gain value being a value representing an  
37 amount by which it is desired that said temporal system  
38 response matrix estimate should be allowed to affect an  
39 overall outcome, and said temporal system response  
40 matrix being an estimate of an actual system response

1 matrix, said actual system response matrix representing  
2 an ideal measurement of actual system response  
3 characteristics which cannot actually be achieved; and

4 a second comparator means, logically situated  
5 within said digital controller after said buffering  
6 means, for comparing a current drive amplitude matrix  
7 and said compensated error matrix and for producing an  
8 updated drive amplitude matrix as an output, said  
9 current drive amplitude matrix being a digital  
10 equivalent of the plurality of sinewaves used for  
11 powering the exciters, which current drive amplitude  
12 matrix is returned to said second comparator by means of  
13 a feed back loop functioning to return the current drive  
14 amplitude matrix to the second comparator such that the  
15 current drive amplitude matrix is an input to the second  
16 comparator used in producing the updated drive amplitude  
17 matrix, said compensated error matrix being the output  
18 from the buffering means, and said updated drive  
19 amplitude matrix serving to replace said current drive  
20 amplitude matrix on a next subsequent cycle such that  
21 the digital controller produces a continuing series of  
22 updated drive amplitude matrices.  
23

24 16. The improved system of Claim 15, wherein:  
25 said adjustment gain value is a complex number.  
26

27 17. The improved system of Claim 15, wherein:  
28 said adjustment gain value is determined during a  
29 learning loop, said learning loop being a cycle of  
30 operation of the system wherein a learning loop gain  
31 value is substituted for said adjustment gain value and  
32 wherein system response to drive signal produced during  
33 said learning loop is measured and used to calculate an  
34 appropriate value for said adjustment gain value.  
35

36 18. The improved system of Claim 17, wherein:  
37 said learning loop gain value is initially  
38 selected to be a real number less than 1.0.  
39

40 19. The improved system of Claim 17, wherein:

1           said learning loop gain value is allowed to  
2    approach a value of 1.0 as differences between  
3    succeeding of the control response vectors becomes less.  
4

5 20.   The improved system of Claim 17, wherein:

6           each of said learning loops is followed by a  
7    control loop, said control loop being a cycle of  
8    operation of the system wherein said adjustment gain  
9    value is used to buffer the system impedance matrix such  
10   that the system impedance matrix is updated to approach  
11   in value the actual system response matrix; and

12          each of said control loops is followed by a  
13   learning loop at least until the system is under  
14   control, as indicated by a value of said adjustment gain  
15   value near unity.  
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# INTERNATIONAL SEARCH REPORT

International Application No **PCT/US90/02761**

<b>I. CLASSIFICATION OF SUBJECT MATTER</b> (If several classification symbols apply, indicate all) <sup>1</sup> According to International Patent Classification (IPC) or to both National Classification and IPC <div style="margin-left: 40px;"> <b>IPC (5):</b> G01M 7/00  <b>US. CL.:</b> 73/664         </div>						
<b>II. FIELDS SEARCHED</b> <div style="text-align: center; margin-top: 10px;">Minimum Documentation Searched <sup>4</sup></div> <table style="width: 100%; border: none;"> <tr> <td style="width: 30%; border: none;">Classification System <sup>1</sup></td> <td style="border: none;">Classification Symbols</td> </tr> <tr> <td style="border: none; padding-top: 10px;">U.S.</td> <td style="border: none; padding-top: 10px;">73/664, 602; 364/508, 512; 340/683</td> </tr> </table> <div style="text-align: center; margin-top: 10px;">Documentation Searched other than Minimum Documentation to the Extent that such Documents are Included in the Fields Searched <sup>5</sup></div>			Classification System <sup>1</sup>	Classification Symbols	U.S.	73/664, 602; 364/508, 512; 340/683
Classification System <sup>1</sup>	Classification Symbols					
U.S.	73/664, 602; 364/508, 512; 340/683					
<b>III. DOCUMENTS CONSIDERED TO BE RELEVANT</b> <sup>14</sup>						
Category <sup>8</sup>	Citation of Document, <sup>16</sup> with indication, where appropriate, of the relevant passages <sup>17</sup>	Relevant to Claim No. <sup>15</sup>				
A	US. A. 4,061,017 (SLOANE ET AL) 06 December 1977 See column 5, lines 5-37	1-20				
A	US, A, 4,181,029 (TALBOTT, JR) 01 January 1980 See the abstract of the disclosure	1-20				
A	US, A, 3,710,082 (SLOANE ET AL) 09 January 1973 See the abstract of the disclosure	1-20				
<div style="display: flex; justify-content: space-between;"> <div style="width: 48%;"> <p><sup>9</sup> Special categories of cited documents: <sup>13</sup></p> <p>"A" document defining the general state of the art which is not considered to be of particular relevance</p> <p>"E" earlier document but published on or after the international filing date</p> <p>"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)</p> <p>"O" document referring to an oral disclosure, use, exhibition or other means</p> <p>"P" document published prior to the international filing date but later than the priority date claimed</p> </div> <div style="width: 48%;"> <p>"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention</p> <p>"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step</p> <p>"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.</p> <p>"&amp;" document member of the same patent family</p> </div> </div>						
<b>IV. CERTIFICATION</b>						
Date of the Actual Completion of the International Search <sup>2</sup>  <div style="text-align: center; font-weight: bold;">01 NOVEMBER 1990</div>		Date of Mailing of this International Search Report <sup>3</sup>  <div style="text-align: center; font-weight: bold; font-size: 1.2em;">13 FEB 1991</div>				
International Searching Authority <sup>1</sup>  <div style="text-align: center; font-weight: bold;">ISA/US</div>		Signature of Authorized Officer <sup>20</sup> <div style="text-align: center;"> <div style="text-align: center; font-weight: bold;">LOUIS M. ARANA</div> </div>				

1/2

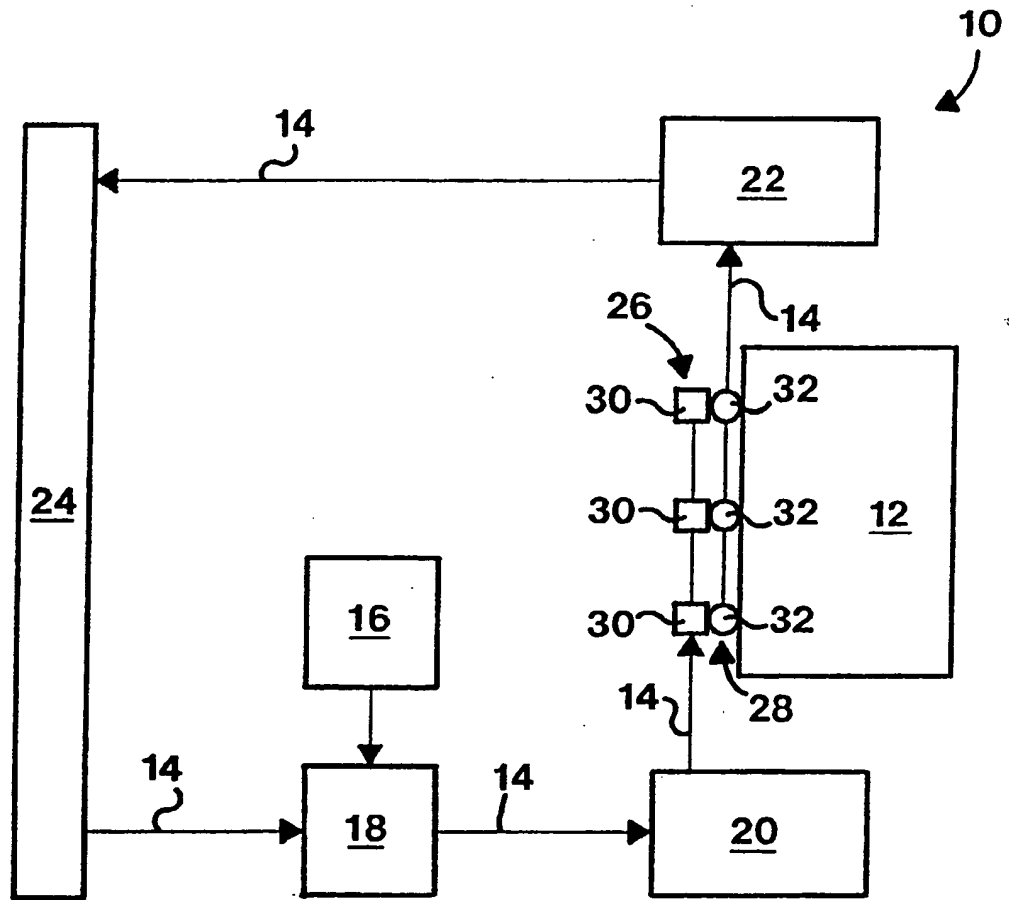


FIG. 1

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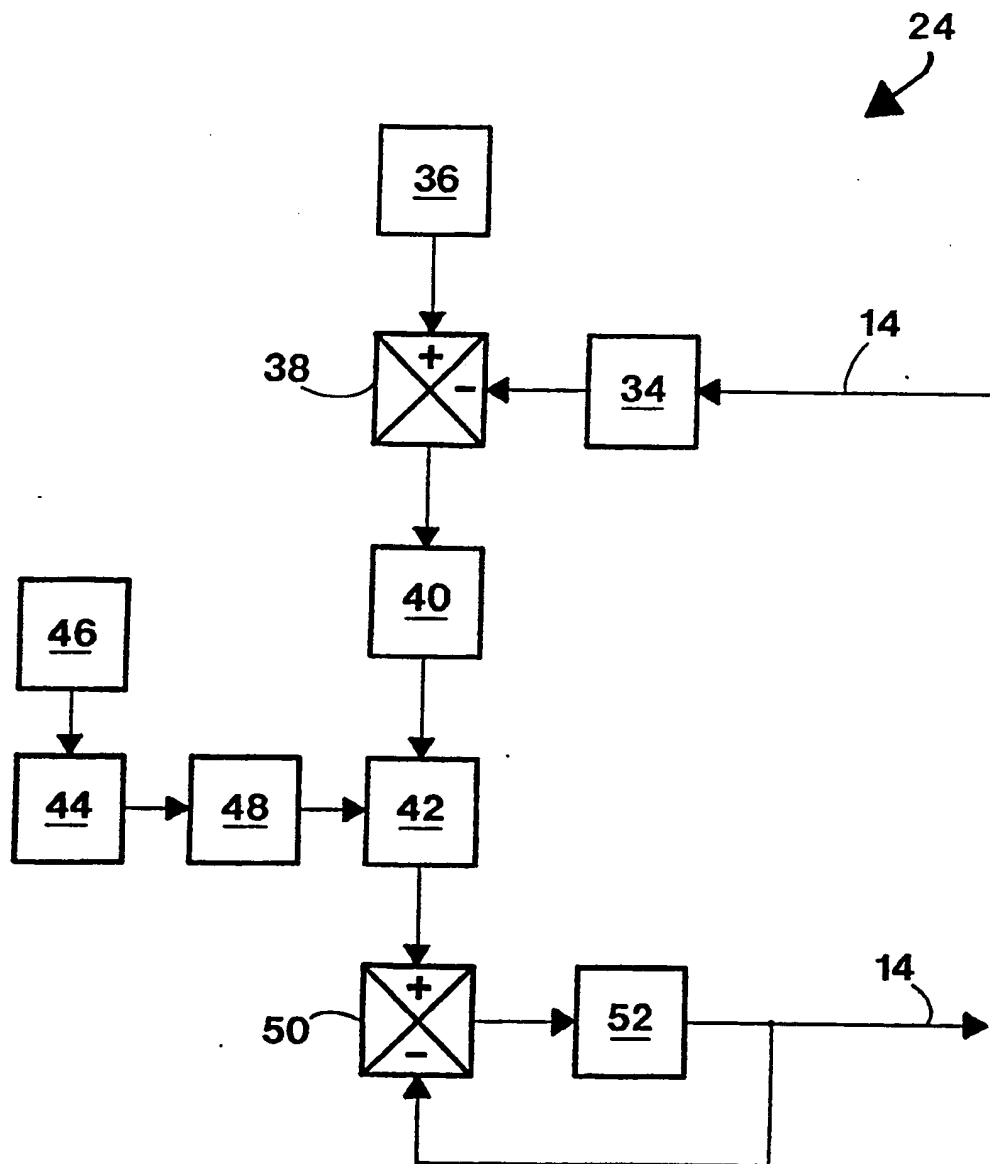


FIG. 2